



MEETING LOG

SUBJECT: ASTM F15.42 Furniture Subcommittee's New Anti-Tip Technology Task Group Meeting Log

FY 24 OP PLAN ENTRY: Clothing Storage Unit (CSU) Tip-over

DATE OF MEETING: 6/25/2024

LOCATION OF MEETING: Virtual

CPSC STAFF FILING MEETING LOG: Kristen Talcott

FILING DATE: 7/3/2024

CPSC ATTENDEE(S): Kristen Talcott (ESHF), Daniel Taxier (ESMC)

NON-CPSC ATTENDEE(S): Contact ASTM for the full attendee list

Summary of Meeting:

This was the first meeting of the task group, which was formed at the May 23, 2024 ASTM F15.42 Furniture Subcommittee meeting to discuss a potential new anti-tip device for clothing storage units (CSUs) and potential implications for stability testing in ASTM F3096, *Standard Performance Specification for Tipover Restraint(s) Used with Clothing Storage Unit(s)*, and/or ASTM F2057, *Standard Safety Specification for Clothing Storage Units*. The device mounts under a CSU and has a sensor that is designed to detect when the CSU starts to tip. When a tip is detected, the device releases a spring-loaded foot that is intended to catch the CSU before it fully tips over. The device is also designed to sound an alarm when the tip is detected. In this meeting, task group members discussed the device, which is currently in development, with the manufacturer.

The manufacturer provided two presentations to the task group: the first was on the device's mechanism and the second was on reliability testing. Discussion about the device included:

- is there potential for injury to toes when the foot releases,
- how loud is the alarm,
- how is the device installed on the CSU,
- what is the effect of CSU design on the required foot length and release speed, and
- what is the effect of carpet on performance?

Task group members also questioned whether the device would be considered an anti-tip device under ASTM F3096 or if it would be considered part of the CSU under ASTM F2057.

Next Steps: The task group lead plans to hold another meeting with the manufacturer in 1-2 months to discuss progress on device development and testing.